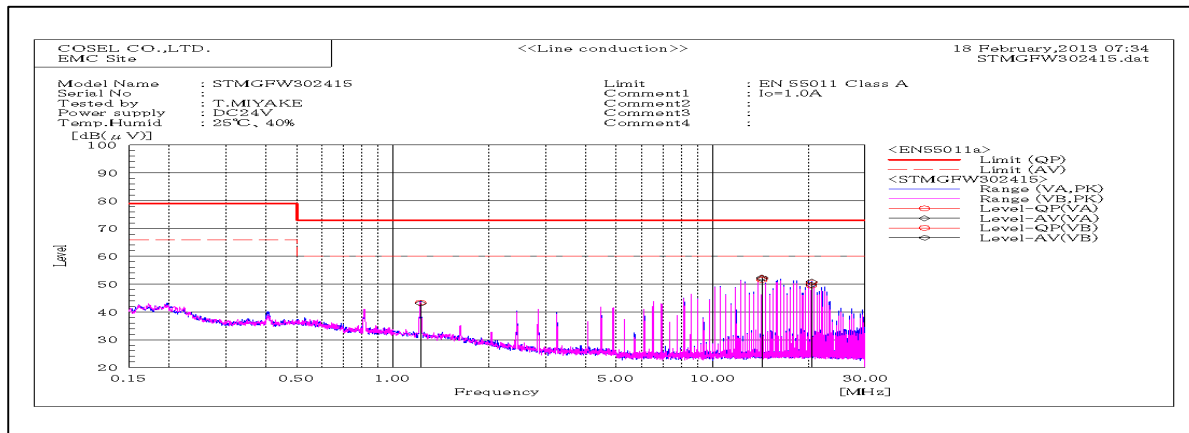
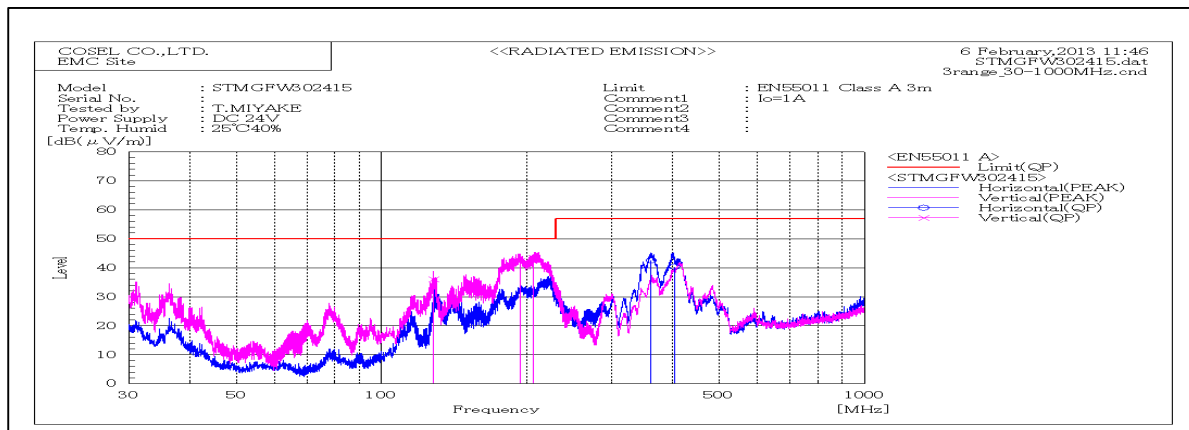


DATA SHEET		Date	18-Feb-13
Model	STMGFW302415	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake



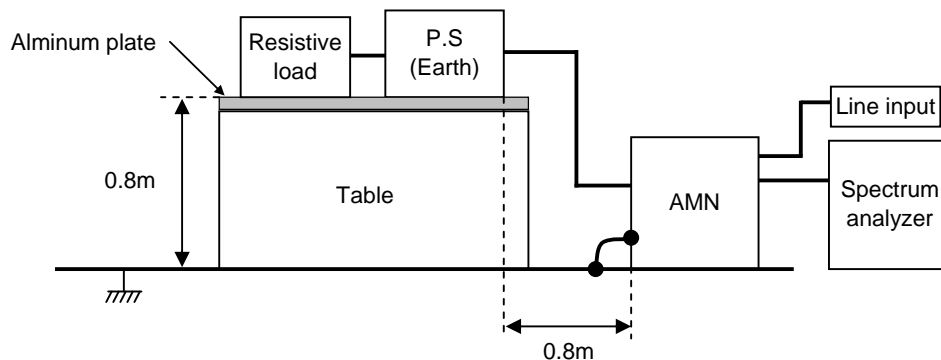
Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
1.22198		VA	23.1	22.8	20.2	43.3	43	73	60	29.7	17	Pass	
14.2571		VB	30.6	31	20.9	51.5	51.9	73	60	21.5	8.1	Pass	
14.256		VA	31	31.4	21	52	52.4	73	60	21	7.6	Pass	
20.3669		VB	28.3	28.5	21.2	49.5	49.7	73	60	23.5	10.3	Pass	
20.36575		VA	29.4	29.6	21.2	50.6	50.8	73	60	22.4	9.2	Pass	



Frequency MHz	Polarization	Stability	Reading dB(uV)		Space Loss dB	Level dB(mW)		Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV					
128.145	V	Stable	53.5		-17.4	36.1		13.9	Pass	104	356	
193.475	V	Stable	58.3		-15.8	42.5		7.5	Pass	104	69	
206.534	V	Stable	59		-15.7	43.3		6.7	Pass	106	339	
361.681	H	Stable	55.4		-12.8	42.6		14.4	Pass	104	272	
404.559	H	Stable	53.1		-12.7	40.4		16.6	Pass	106	285	

DATA SHEET		Date	18-Feb-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake

## 1. Line conduction



## 2. Radiated emission

